Bus buffer/line driver; 3-state

Rev. 09 — 22 June 2009

**Product data sheet** 

### 1. General description

74AHC1G125 and 74AHCT1G125 are high-speed Si-gate CMOS devices. They provide one non-inverting buffer/line driver with 3-state output. The 3-state output is controlled by the output enable input ( $\overline{OE}$ ). A HIGH at  $\overline{OE}$  causes the output to assume a high-impedance OFF-state.

The AHC device has CMOS input switching levels and supply voltage range 2 V to 5.5 V.

The AHCT device has TTL input switching levels and supply voltage range 4.5 V to 5.5 V.

### 2. Features

- Symmetrical output impedance
- High noise immunity
- Low power dissipation
- Balanced propagation delays
- Multiple package options
- ESD protection:
  - HBM JESD22-A114E: exceeds 2000 V
  - MM JESD22-A115-A: exceeds 200 V
  - CDM JESD22-C101C: exceeds 1000 V
- Specified from –40 °C to +125 °C

### 3. Ordering information

#### Table 1.Ordering information

Type number	Package									
	Temperature range	Name	Description	Version						
74AHC1G125GW	–40 °C to +125 °C	TSSOP5	plastic thin shrink small outline package; 5 leads; body width 1.25 mm	SOT353-1						
74AHCT1G125GW										
74AHC1G125GV	–40 °C to +125 °C	SC-74A	plastic surface-mounted package; 5 leads	SOT753						
74AHCT1G125GV										
74AHC1G125GM	–40 °C to +125 °C	XSON6	plastic extremely thin small outline package; no	SOT886						
74AHCT1G125GM			leads; 6 terminals; body $1 \times 1.45 \times 0.5$ mm							
74AHC1G125GF	–40 °C to +125 °C	XSON6	plastic extremely thin small outline package;	SOT891						
74AHCT1G125GF			no leads; 6 terminals; body $1 \times 1 \times 0.5$ mm							



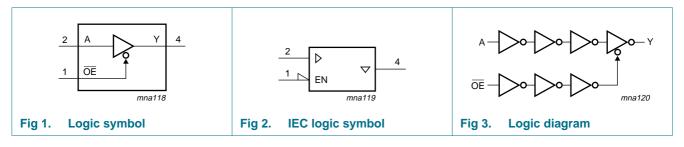
Bus buffer/line driver; 3-state

### 4. Marking

Table 2.   Marking codes	
Type number	Marking <sup>[1]</sup>
74AHC1G125GW	AM
74AHCT1G125GW	СМ
74AHC1G125GV	A25
74AHCT1G125GV	C25
74AHC1G125GM	AM
74AHCT1G125GM	СМ
74AHC1G125GF	AM
74AHCT1G125GF	СМ

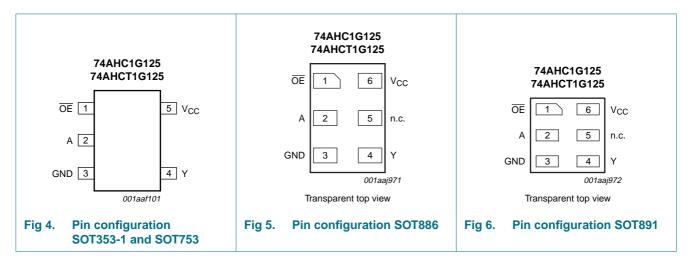
[1] The pin 1 indicator is located on the lower left corner of the device, below the marking code.

## 5. Functional diagram



## 6. Pinning information

### 6.1 Pinning



74AHC\_AHCT1G125\_9

Bus buffer/line driver; 3-state

### 6.2 Pin description

Table 3. Pi	n description		
Symbol	Pin		Description
	SOT353-1/SOT753	SOT886/SOT891	
OE	1	1	output enable input
A	2	2	data input
GND	3	3	ground (0 V)
Y	4	4	data output
n.c.	-	5	not connected
V <sub>CC</sub>	5	6	supply voltage

### 7. Functional description

#### Table 4.Function table

H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state

Inputs OE		Output
ŌE	Α	Y
L	L	L
L	Н	Н
н	Х	Z

## 8. Limiting values

#### Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage		-0.5	+7.0	V
VI	input voltage		-0.5	+7.0	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < -0.5 V	<u>[1]</u> –20	-	mA
I <sub>OK</sub>	output clamping current	$V_{\rm O}$ < –0.5 V or V_{\rm O} > V <sub>CC</sub> + 0.5 V	<u>[1]</u> _	±20	mA
lo	output current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$	-	±25	mA
I <sub>CC</sub>	supply current		-	75	mA
I <sub>GND</sub>	ground current		-75	-	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	total power dissipation	$T_{amb} = -40 \ ^{\circ}C \text{ to } +125 \ ^{\circ}C$	[2] _	250	mW
,					

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] For TSSOP5 and SC-74A packages: above 87.5 °C the value of P<sub>tot</sub> derates linearly with 4.0 mW/K. For XSON6 packages: above 118 °C the value of P<sub>tot</sub> derates linearly with 7.8 mW/K.

Bus buffer/line driver; 3-state

## 9. Recommended operating conditions

#### Table 6. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	74	AHC1G1	25	74	Unit			
			Min	Тур	Max	Min	Тур	Max	
V <sub>CC</sub>	supply voltage		2.0	5.0	5.5	4.5	5.0	5.5	V
VI	input voltage		0	-	5.5	0	-	5.5	V
Vo	output voltage		0	-	$V_{CC}$	0	-	$V_{CC}$	V
T <sub>amb</sub>	ambient temperature		-40	+25	+125	-40	+25	+125	°C
$\Delta t / \Delta V$	input transition rise	$V_{CC}$ = 3.3 V $\pm$ 0.3 V	-	-	100	-	-	-	ns/V
	and fall rate	$V_{CC}=5.0~V\pm0.5~V$	-	-	20	-	-	20	ns/V

## **10. Static characteristics**

#### Table 7. Static characteristics

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		-40 °C 1	to +85 °C	_40 °C t	o +125 °C	Unit
			Min	Тур	Max	Min	Max	Min	Max	1
74AHC1	G125	'								
V <sub>IH</sub>	HIGH-level	V <sub>CC</sub> = 2.0 V	1.5	-	-	1.5	-	1.5	-	V
	input voltage	V <sub>CC</sub> = 3.0 V	2.1	-	-	2.1	-	2.1	-	V
		$V_{CC} = 5.5 V$	3.85	-	-	3.85	-	3.85	-	V
V <sub>IL</sub>	LOW-level	$V_{CC} = 2.0 V$	-	-	0.5	-	0.5	-	0.5	V
	input voltage	V <sub>CC</sub> = 3.0 V	-	-	0.9	-	0.9	-	0.9	V
		$V_{CC} = 5.5 V$	-	-	1.65	-	1.65	-	1.65	V
V <sub>OH</sub>	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_0 = -50 \ \mu\text{A}; \ V_{CC} = 2.0 \ \text{V}$	1.9	2.0	-	1.9	-	1.9	-	V
		$I_{O} = -50 \ \mu\text{A}; \ V_{CC} = 3.0 \ \text{V}$	2.9	3.0	-	2.9	-	2.9	-	V
		$I_0 = -50 \ \mu\text{A}; \ V_{CC} = 4.5 \ \text{V}$	4.4	4.5	-	4.4	-	4.4	-	V
		$I_{O} = -4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.58	-	-	2.48	-	2.40	-	V
		$I_0 = -8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.94	-	-	3.8	-	3.70	-	V
V <sub>OL</sub>	LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}$								
	output voltage	$I_0 = 50 \ \mu A; \ V_{CC} = 2.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_0 = 50 \ \mu A; \ V_{CC} = 3.0 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_{O} = 50 \ \mu\text{A}; \ V_{CC} = 4.5 \ V$	-	0	0.1	-	0.1	-	0.1	V
		$I_0 = 4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.36	-	0.44	-	0.55	V
		$I_0$ = 8.0 mA; $V_{CC}$ = 4.5 V	-	-	0.36	-	0.44	-	0.55	V
I <sub>OZ</sub>	OFF-state output current	$V_I = V_{CC} \text{ or GND};$ $V_{CC} = 5.5 \text{ V}$	-	-	0.25	-	2.5	-	10	μΑ
lı	input leakage current	V <sub>I</sub> = 5.5 V or GND; V <sub>CC</sub> = 0 V to 5.5 V	-	-	0.1	-	1.0	-	2.0	μΑ
I <sub>CC</sub>	supply current		-	-	1.0	-	10	-	40	μΑ

Bus buffer/line driver; 3-state

		to $GND$ (ground = 0 V).		05 00		40.00	1 OF 00	40.00 (	405 00	Unit
Symbol	Parameter	Conditions		25 °C	1	-40 °C	to +85 °C	–40 °C t	o +125 °C	Unit
			Min	Тур	Max	Min	Max	Min	Max	
CI	input capacitance		-	1.5	10	-	10	-	10	pF
74AHCT	1G125									
VIH	HIGH-level input voltage	$V_{CC}$ = 4.5 V to 5.5 V	2.0	-	-	2.0	-	2.0	-	V
VIL	LOW-level input voltage	$V_{CC}$ = 4.5 V to 5.5 V	-	-	0.8	-	0.8	-	0.8	V
V <sub>OH</sub>	HIGH-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
	output voltage	I <sub>O</sub> = -50 μA	4.4	4.5	-	4.4	-	4.4	-	V
		I <sub>O</sub> = -8.0 mA	3.94	-	-	3.8	-	3.70	-	V
V <sub>OL</sub>	V <sub>OL</sub> LOW-level	$V_{I} = V_{IH} \text{ or } V_{IL}; V_{CC} = 4.5 \text{ V}$								
	output voltage	I <sub>O</sub> = 50 μA	-	0	0.1	-	0.1	-	0.1	V
		l <sub>O</sub> = 8.0 mA	-	-	0.36	-	0.44	-	0.55	V
I <sub>OZ</sub>	OFF-state output current	$V_1 = V_{CC} \text{ or GND};$ $V_{CC} = 5.5 \text{ V}$	-	-	0.25	-	2.5	-	10	μΑ
lı	input leakage current	$V_1 = 5.5 V \text{ or GND};$ $V_{CC} = 0 V \text{ to } 5.5 V$	-	-	0.1	-	1.0	-	2.0	μΑ
I <sub>CC</sub>	supply current		-	-	1.0	-	10	-	40	μΑ
Δl <sub>CC</sub>	additional supply current	per input pin; $V_I = 3.4 V$ ; other inputs at $V_{CC}$ or GND; $I_O = 0 A$ ; $V_{CC} = 5.5 V$	-	-	1.35	-	1.5	-	1.5	mA
CI	input capacitance		-	1.5	10	-	10	-	10	pF

## Table 7. Static characteristics ...continued Voltages are referenced to GND (ground = 0.V)

## **11. Dynamic characteristics**

#### Table 8.Dynamic characteristics

GND = 0 V; For test circuit see Figure 9.

Symbol	Parameter	Conditions		25 °C		_40 °C t	to +85 °C	–40 °C to +125 °C		Unit	
				Min	Тур	Max	Min	Max	Min	Max	
74AHC1	G125										
t <sub>pd</sub>		A to Y; see Figure 7	<u>[1]</u>								
delay	$V_{CC}$ = 3.0 V to 3.6 V	[2]									
		C <sub>L</sub> = 15 pF		-	4.7	8.0	1.0	9.5	1.0	11.5	ns
		C <sub>L</sub> = 50 pF		-	6.6	11.5	1.0	13.0	1.0	14.5	ns
		$V_{CC}$ = 4.5 V to 5.5 V	[3]								
		C <sub>L</sub> = 15 pF		-	3.4	5.5	1.0	6.5	1.0	7.0	ns
		C <sub>L</sub> = 50 pF		-	4.8	7.5	1.0	8.5	1.0	9.5	ns

Bus buffer/line driver; 3-state

Symbol	Parameter	Conditions			25 °C		<b>−40 °C</b> 1	to +85 °C	–40 °C to +125 °C		Unit
				Min	Тур	Max	Min	Max	Min	Max	
en	enable time	OE to Y; see Figure 8	<u>[1]</u>								
		$V_{CC}$ = 3.0 V to 3.6 V	[2]								
		C <sub>L</sub> = 15 pF		-	5.0	8.0	1.0	9.5	1.0	11.5	ns
		C <sub>L</sub> = 50 pF		-	6.9	11.5	1.0	13.0	1.0	14.5	ns
		$V_{CC}$ = 4.5 V to 5.5 V	[3]								
		C <sub>L</sub> = 15 pF		-	3.6	5.1	1.0	6.0	1.0	6.5	ns
		C <sub>L</sub> = 50 pF		-	4.9	7.5	1.0	8.5	1.0	9.5	ns
dis	disable time	OE to Y; see Figure 8	<u>[1]</u>								
		$V_{CC}$ = 3.0 V to 3.6 V	[2]								
		C <sub>L</sub> = 15 pF		-	6.0	9.7	1.0	11.5	1.0	12.5	ns
		C <sub>L</sub> = 50 pF		-	8.3	13.2	1.0	15.0	1.0	16.5	ns
		$V_{CC}$ = 4.5 V to 5.5 V	[3]								
		C <sub>L</sub> = 15 pF		-	4.1	6.8	1.0	8.0	1.0	8.5	ns
		C <sub>L</sub> = 50 pF		-	5.7	8.8	1.0	10.0	1.0	11.0	ns
C <sub>PD</sub>	power dissipation capacitance	per buffer; $C_L = 50 \text{ pF}; \text{ f} = 1 \text{ MHz};$ $V_I = \text{GND to } V_{CC}$	<u>[4]</u>	-	9	-	-	-	-	-	pF
74AHCT	1G125										
pd	propagation	A to Y; see Figure 7	<u>[1]</u>								
	delay	$V_{CC}$ = 4.5 V to 5.5 V	[3]								
		C <sub>L</sub> = 15 pF		-	3.4	5.5	1.0	6.5	1.0	7.0	ns
		C <sub>L</sub> = 50 pF		-	4.8	7.5	1.0	8.5	1.0	9.5	ns
en	enable time	OE to Y; see Figure 8	[1]								
		$V_{CC}$ = 4.5 V to 5.5 V	[3]								
		C <sub>L</sub> = 15 pF		-	3.9	5.1	1.0	6.0	1.0	6.5	ns
		C <sub>L</sub> = 50 pF		-	5.1	7.5	1.0	8.5	1.0	9.5	ns
dis	disable time	OE to Y; see Figure 8	[1]								
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	[3]								
		C <sub>L</sub> = 15 pF		-	4.5	6.8	1.0	8.0	1.0	8.5	ns
		$C_{L} = 50  pF$		-	6.1	8.8	1.0	10.0	1.0	11.0	ns

# Table 8.Dynamic characteristics ... continuedGND = 0 V; For test circuit see Figure 9.

Bus buffer/line driver; 3-state

Symbol	bol Parameter Conditions			25 °C		<b>−40 °C to +85 °C</b>		−40 °C to +125 °C		Uni	
				Min	Тур	Max	Min	Max	Min	Max	
C <sub>PD</sub>		per buffer; $C_L = 50 \text{ pF}; f = 1 \text{ MHz};$ $V_I = \text{GND to } V_{CC}$	<u>[4]</u>	-	11	-	-	-	-	-	pF

### Table 8. Dynamic characteristics ... continued

 $t_{en}$  is the same as  $t_{PZL}$  and  $t_{PZH}$ .  $t_{dis}$  is the same as  $t_{PLZ}$  and  $t_{PHZ}$ .

[2] Typical values are measured at V\_{CC} = 3.3 V.

- [3] Typical values are measured at V<sub>CC</sub> = 5.0 V.
- [4]  $C_{PD}$  is used to determine the dynamic power dissipation  $P_D$  ( $\mu W$ ).

 $P_{D} = C_{PD} \times V_{CC}^{2} \times f_{i} + \sum (C_{L} \times V_{CC}^{2} \times f_{o}) \text{ where:}$ 

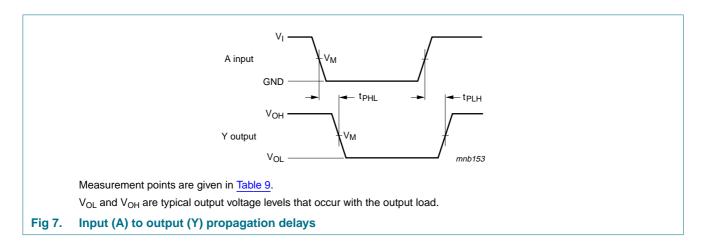
 $f_i$  = input frequency in MHz;

 $f_o$  = output frequency in MHz;

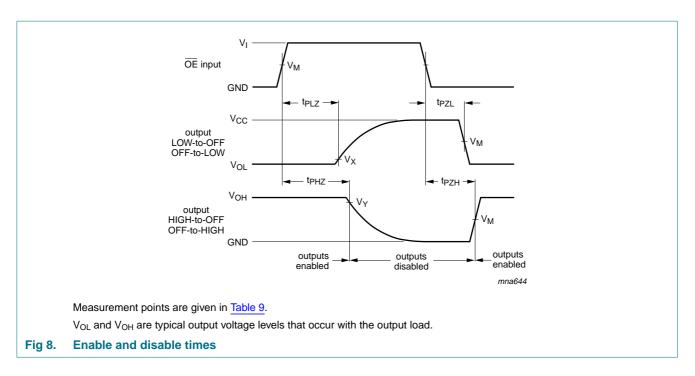
 $C_L$  = output load capacitance in pF;

V<sub>CC</sub> = supply voltage in Volts.

## 12. Waveforms



Bus buffer/line driver; 3-state



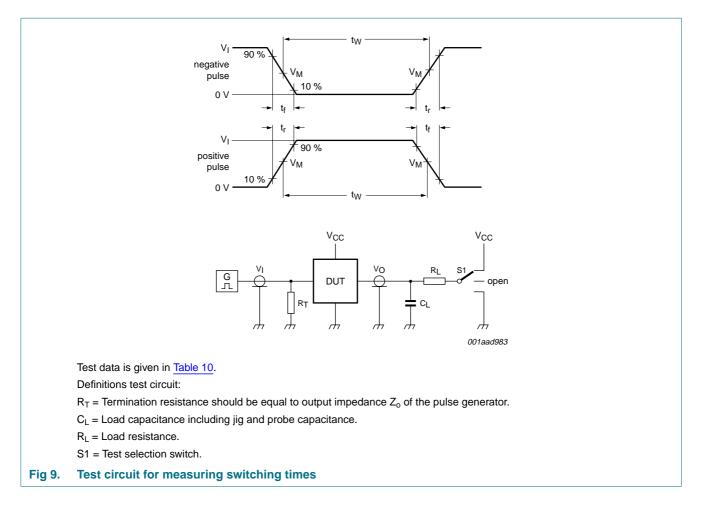
#### Table 9.Measurement point

Туре	Inputs		Output				
	VI	V <sub>M</sub>	V <sub>M</sub>	V <sub>X</sub>	V <sub>Y</sub>		
74AHC1G125	GND to V <sub>CC</sub>	0.5V <sub>CC</sub>	0.5V <sub>CC</sub>	V <sub>OL</sub> + 0.3 V	V <sub>OH</sub> – 0.3 V		
74AHCT1G125	GND to 3.0 V	1.5 V	0.5V <sub>CC</sub>	V <sub>OL</sub> + 0.3 V	V <sub>OH</sub> – 0.3 V		

### **NXP Semiconductors**

# 74AHC1G125; 74AHCT1G125

Bus buffer/line driver; 3-state

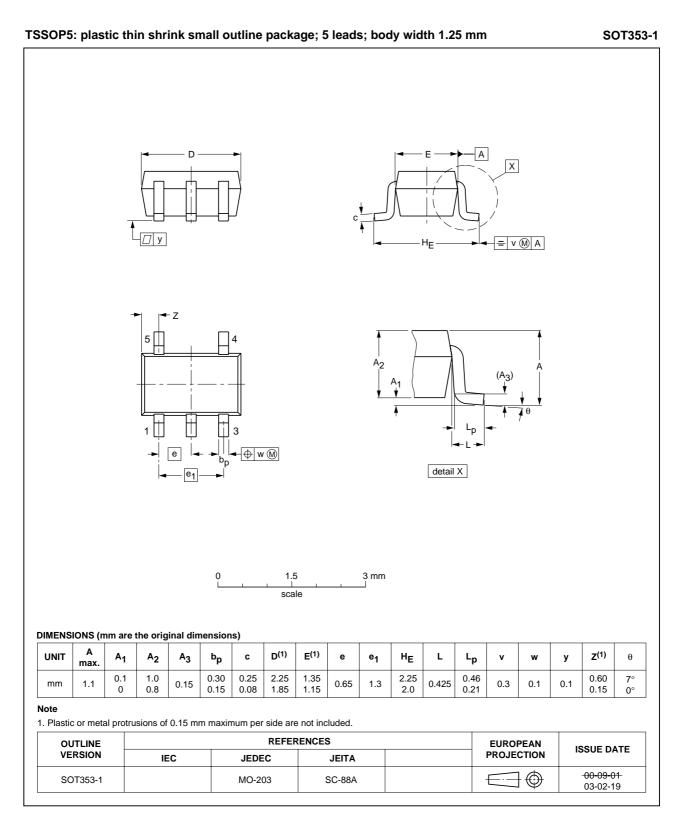


#### Table 10. Test data

Туре	Input		Load		S1 position		
	VI	t <sub>r</sub> , t <sub>f</sub>	CL	RL	t <sub>PHL</sub> , t <sub>PLH</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub>
74AHC1G125	V <sub>CC</sub>	≤ 3 ns	15 pF, 50 pF	1 kΩ	open	GND	V <sub>CC</sub>
74AHCT1G125	3 V	≤ 3 ns	15 pF, 50 pF	1 kΩ	open	GND	V <sub>CC</sub>

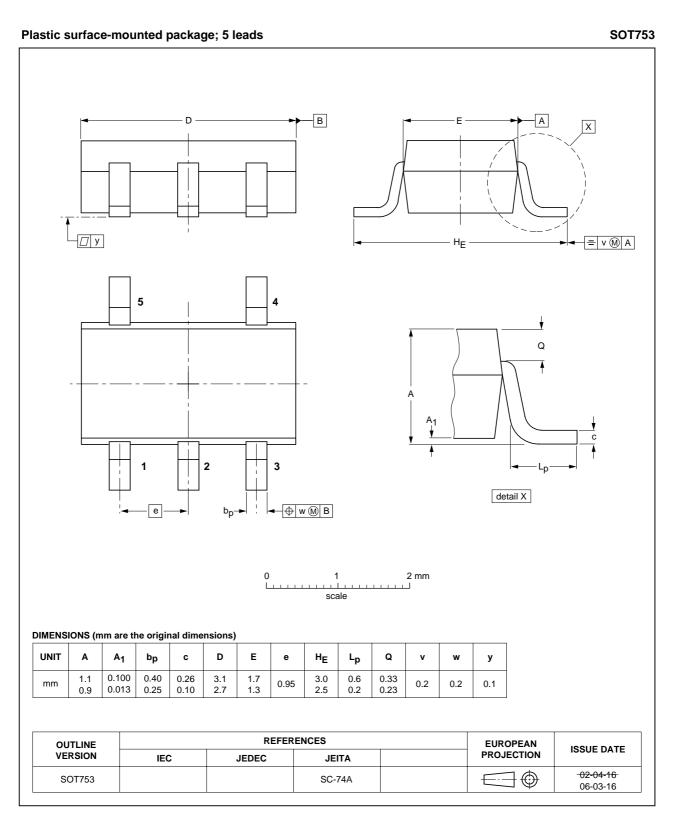
Bus buffer/line driver; 3-state

### 13. Package outline



#### Fig 10. Package outline SOT353-1 (TSSOP5)

Bus buffer/line driver; 3-state



#### Fig 11. Package outline SOT753 (SC-74A)

Bus buffer/line driver; 3-state

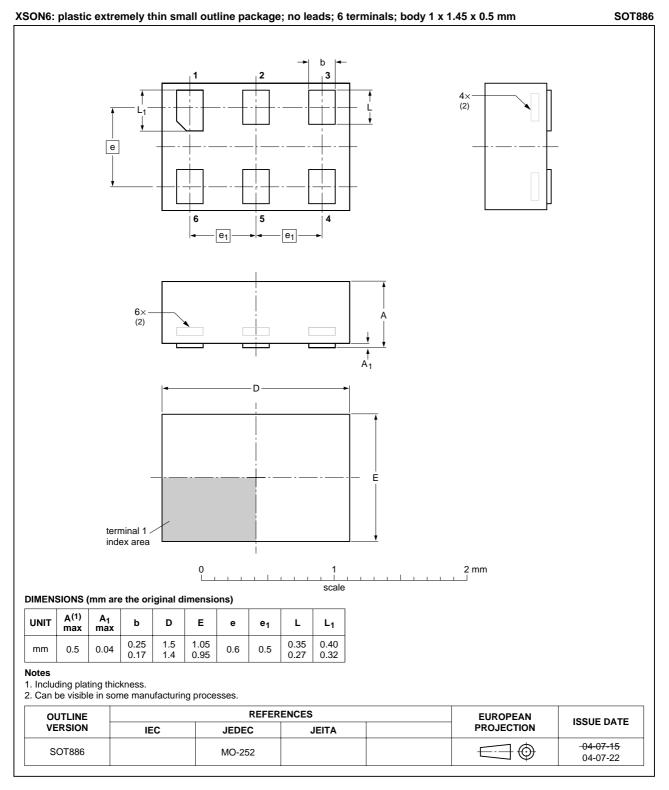
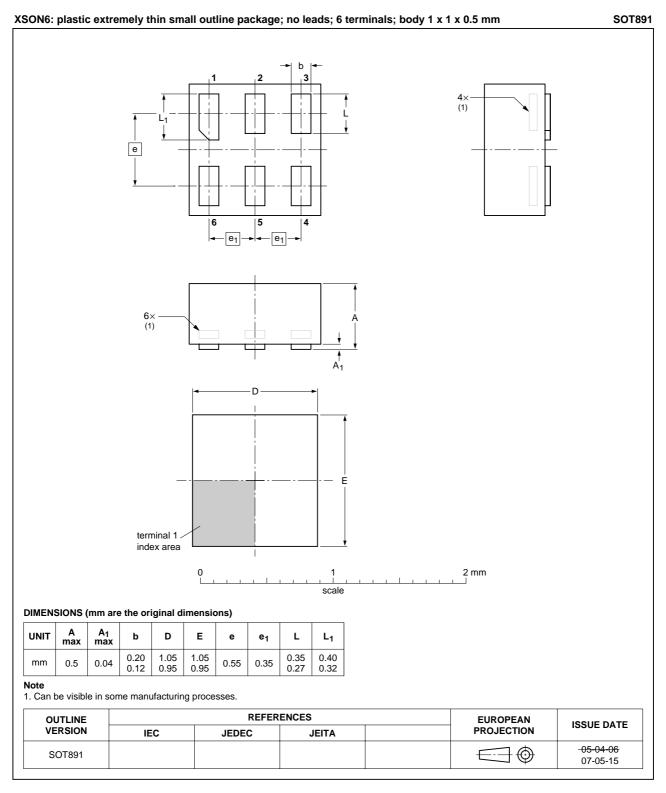


Fig 12. Package outline SOT886 (XSON6)

74AHC\_AHCT1G125\_9

Bus buffer/line driver; 3-state



#### Fig 13. Package outline SOT891 (XSON6)

74AHC\_AHCT1G125\_9

Bus buffer/line driver; 3-state

## 14. Abbreviations

AcronymDescriptionCMOSComplementary Metal Oxide SemiconductorCDMCharged Device ModelDUTDevice Under TestESDElectroStatic DischargeUDMUwman Dadiu Medal	. Abbreviations			
CDMCharged Device ModelDUTDevice Under TestESDElectroStatic Discharge				
DUTDevice Under TestESDElectroStatic Discharge				
ESD ElectroStatic Discharge				
LIDM Liveren Dedu Medel				
HBM Human Body Model				
MM Machine Model				
TTL Transistor-Transistor Logic				

## 15. Revision history

Table 12.Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes
74AHC_AHCT1G125_9	20090622	Product data sheet	-	74AHC_AHCT1G125_8
Modifications:	<ul> <li>Updated feat</li> </ul>	ures with multiple package opt	tion in <mark>Sectio</mark>	on <u>2</u> .
74AHC_AHCT1G125_8	20090409	Product data sheet	-	74AHC_AHCT1G125_7
Modifications:	<ul> <li>Package SO</li> </ul>	T886 and SOT891 added in Se	ection 3, Sec	tion 4 and Section 13.
74AHC_AHCT1G125_7	20070707	Product data sheet	-	74AHC_AHCT1G125_6
74AHC_AHCT1G125_6	20020606	Product specification	-	74AHC_AHCT1G125_5
74AHC_AHCT1G125_5	20020322	Product specification	-	74AHC_AHCT1G125_4
74AHC_AHCT1G125_4	20010222	Product specification	-	74AHC_AHCT1G125_3
74AHC_AHCT1G125_3	19990615	Product specification	-	74AHC_AHCT1G125_N_2
74AHC_AHCT1G125_N_2	19981207	Preliminary specification	-	74AHC_AHCT1G125_N_1
74AHC_AHCT1G125_N_1	19981125	Preliminary specification	-	-

## 16. Legal information

#### 16.1 Data sheet status

Document status <sup>[1][2]</sup>	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

#### 16.2 Definitions

**Draft** — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

#### 16.3 Disclaimers

**General** — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

**Right to make changes** — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental

# damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

**Applications** — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at <a href="http://www.nxp.com/profile/terms">http://www.nxp.com/profile/terms</a>, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

**No offer to sell or license** — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

**Export control** — This document as well as the item(s) described herein may be subject to export control regulations. Export might require a prior authorization from national authorities.

#### 16.4 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

## 17. Contact information

For more information, please visit: http://www.nxp.com

For sales office addresses, please send an email to: salesaddresses@nxp.com

Bus buffer/line driver; 3-state

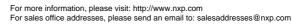
### **18. Contents**

1	General description 1
2	Features 1
3	Ordering information 1
4	Marking 2
5	Functional diagram 2
6	Pinning information 2
6.1	Pinning 2
6.2	Pin description 3
7	Functional description 3
8	Limiting values 3
9	Recommended operating conditions 4
10	Static characteristics 4
11	Dynamic characteristics 5
12	Waveforms 7
13	Package outline 10
14	Abbreviations 14
15	Revision history 14
16	Legal information 15
16.1	Data sheet status 15
16.2	Definitions
16.3	Disclaimers
16.4	Trademarks 15
17	Contact information 15
18	Contents 16

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

© NXP B.V. 2009.

All rights reserved.



Date of release: 22 June 2009 Document identifier: 74AHC\_AHCT1G125\_9

